

Search Notes

Application/Control No.

10/626,815

Examiner

Sheela C. Chawan

Applicant(s)/Patent under
Reexamination

ICHIKAWA ET AL.

Art Unit

2624

SEARCHED

Class	Subclass	Date	Examiner
382	118, 141	8/14/2006	SCC
"	145, 199	8/14/2006	"
"	217,209	8/14/2006	"
"	278,218	8/14/2006	"
"	260,218	8/14/2006	"
358	1.2	8/14/2006	"
"	443	8/14/2006	"
"	448	8/14/2006	"
704	243,231	8/14/2006	"
"	238,243	8/14/2006	"
451	4	8/14/2006	"
ABOVE	SEARCH	8/14/2006	"
UP-DAT.			

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
382	145, 217	8/14/2006	SCC
358	1.2	8/14/2006	"
704	243	8/14/2006	"
IINTERFERENCE SEARCH, SEE SEARCH HISTORY PRINT OUT.		8/14/2006	"

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST, US-PGPUB, USPAT, EPO,JPO,DERWENT,IBM-TDB, SEE ATTACHED SEARCH HISTORY.	8/14/2006	SCC
382/ 118, 145, 199, 217, 209, 278, 218 260, 218.CCLS. 358/ 1.2, 443, 448.CCLS. 704/243,231.CCLS. US-PATENT ONLY, SEE TEXT.	8/14/2006	"
INVENTOR NAME SEARCH.	8/14/2006	"
SEARCH INSPEC DATA BASE.	8/14/2006	"